

Certified Reference Material

Certificate of Analysis

Product ID: MBH-84X BA2 E

ISO
17034:2016

ISO/IEC
17025:2017

ISO
9001:2015

Product Description: Battery Alloy Pb/Sn/Ca

Revision No.: 000
Revision Date: 05/20/2022

Description and Intended Use: This **Certified Reference Material** is covered under the scope of accreditation to **ISO 17034** by LGC Standards - Manchester, NH. As an ISO 17034 certified reference material, appropriate use of this material will fulfill the certified reference material and traceability requirements for use in **ISO 17025** accredited laboratories. This CRM may come in the form of a solid disk, or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

Certified Values listed in wt.% with associated uncertainties

Ag 0.0061 ±0.0004	Al 0.025 ±0.001	Bi 0.0089 ±0.0008	Ca 0.078 ± 0.003
Cd 0.0058 ±0.0007	Cu 0.0014 ±0.0004	Sb 0.0017 ±0.0003	Sn 0.515 ± 0.009
Zn 0.024 ±0.001			

Indicative Values listed in ppm

As (20)	Hg (70)	In (10)	Mg (30)	Ni (1)	Pb (99.31%)	S (10)
Te (4)						

Homogeneity and Uncertainty: "Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N_{prod} is the number of units produced and N_{min} is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculate uncertainty due to inhomogeneity (U_{hom}). Uncertainty of the material is calculated by equation 2, where $H=U_{hom}$, S = Standard deviation, t = t-value at 95% CI, and n = number of observations.

$$1. N_{MIN} = \max(10, \sqrt[3]{N_{PROD}})$$

$$2. U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$$

Certification Laboratories: Much of the analytical work performed to assess this material has been carried out by laboratories with proven competence, as indicated by their accreditation to ISO 17025. It is an implicit requirement for this accreditation that analytical work should be performed with due traceability, via an unbroken chain of comparisons, each with stated uncertainty, to primary standards such as the mole, or to nationally- or internationally-recognized reference materials. Of the individual results herein, some have traceability (to the mole) via primary analytical methods. Some are traceable to substances of known stoichiometry. Most have traceability via commercial solutions. Furthermore, some results have additional traceability to NIST standards, as part of the analytical calibration or process control.

- Applied Technical Services - Marietta, GA
- Connecticut Metallurgical, Inc. - East Hartford, CT
- Dirats Laboratories - Westfield, MA
- Instytut Metali Niezależnych - Gliwice, Poland
- IMR Test Labs - Lansing, NY
- Inppamet Anodos - Calama, Chile
- LGC Standards - Manchester, NH
- NSL Analytical Services - Cleveland, OH
- Scrooby's Laboratory Services - Benoni, South Africa
- SGS MSI - Melrose Park, IL
- TEC-Eurolab - Campogalliano, Italy
- Universal Scientific Laboratory - Revesby NSW, Australia

Instructions for Use: The test surface is on the opposite side of the labeled surface, which includes the material identification. This material is individually chill cast per piece. This manner of casting can cause the formation of inhomogeneous segregates in the upper, engraved portion of the disk. Therefore, the certification information above is not applicable to within 3mm of the engraved surface. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when not in use. Chips are not recommended for gas analysis.

Period of Validity: The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.


Chuck Goudreau, Certifying Officer

May 20, 2022
Certification Date



ISO 17034 Accredited: Reference Materials
Producer, Certificate # 2848.02
ISO/IEC 17025 Accredited: Chemical Testing,
Certificate # 2848.01

Conditions of Sale and Supply: All CRMs & RMs sold are subject to applicable LGC Standard Terms and Conditions of Sale.



The following data represents all pertinent information reported as it applies to the chemical characterization of this material.

	Ag	Al	As	Bi	Ca	Cd	Cu	Hg	In	Mg	Ni	Pb	S
1	0.0050	0.0220	0.0001	0.0070	0.0700	0.0049	0.0006	0.0060	0.0001	0.00004	0.00004	99.300	0.0003
2	0.0050	0.0226	0.0003	0.0072	0.0740	0.0050	0.0010	0.0072	0.0001	0.0001	0.0001	99.300	0.0011
3	0.0054	0.0240	0.0003	0.0072	0.0740	0.0050	0.0010	<0.0001	0.0001	0.0050	0.0003	99.320	0.0012
4	0.0055	0.0244	0.0004	0.0080	0.0759	0.0050	0.0011	<0.001	0.0030	0.0050	<0.0001		<0.001
5	0.0055	0.0248	0.0006	0.0080	0.0773	0.0050	0.0013		<0.0005	<0.0001	<0.0005		<0.002
6	0.0057	0.0250	0.0048	0.0080	0.0774	0.0050	0.0014		<0.001	<0.0005	<0.001		<0.002
7	0.0059	0.0250	0.0050	0.0088	0.0778	0.0054	0.0015		<0.0010	<0.001	<0.001		<0.0100
8	0.0060	0.0253	<0.0005	0.0090	0.0795	0.0055	0.0016		<0.002	<0.001	<0.0010		
9	0.0060	0.0253	<0.001	0.0092	0.0812	0.0059	0.0018		<0.005	<0.0010	<0.002		
10	0.0065	0.0253	<0.002	0.0092	0.0820	0.0066	0.0018			<0.005	<0.002		
11	0.0070	0.0256	<0.002	0.0098	0.0828	0.0080	0.0026				<0.005		
12	0.0070	0.0264	<0.005	0.0100	0.0880	0.0080	<0.002						
13	0.0070	0.0267	<0.0050	0.0100		<0.005	<0.002						
14	0.0070	0.0277		0.0102			<0.005						
15	0.0074			0.0120									
Mean	0.0061	0.0250	0.0016	0.0089	0.0783	0.0058	0.0014	0.0066	0.0008	0.0025	0.0001	99.307	0.0009
STDV	0.0008	0.0015	0.0022	0.0014	0.0048	0.0012	0.0005	0.0008	0.0015	0.0028	0.0001	0.0115	0.0005
Certified	0.0061	0.025	(0.002)	0.0089	0.078	0.0058	0.0014	(0.007)	(0.001)	(0.003)	(0.0001)	(99.31)	(0.001)
U _{CRM}	0.0004	0.001		0.0008	0.003	0.0007	0.0004						
Methods	I,IM,A,O,X	I,A,O,X,IM	I,A,O,IM,X	I,A,O,X,IM	I,O	I,A,O,IM,X	I,IM,A,O,X	I,A	IM,I,X,O	I,IM,X,O	I,A,IM,X,O	I,X	I,X

	Sb	Sn	Te	Zn
1	0.0013	0.4830	0.0001	0.0200
2	0.0014	0.4945	0.0002	0.0200
3	0.0015	0.5100	0.0002	0.0220
4	0.0016	0.5110	0.0003	0.0228
5	0.0016	0.5170	0.0010	0.0230
6	0.0017	0.5190	<0.0010	0.0232
7	0.0020	0.5200	<0.002	0.0234
8	0.0022	0.5200	<0.002	0.0236
9	<0.0005	0.5208	<0.003	0.0240
10	<0.001	0.5210	<0.005	0.0249
11	<0.001	0.5320		0.0252
12	<0.002	0.5330		0.0253
13	<0.002			0.0270
14	<0.005			0.0274
15				
Mean	0.0017	0.5151	0.0004	0.0237
STDV	0.0003	0.0143	0.0004	0.0022
Certified	0.0017	0.515	(0.0004)	0.024
U _{CRM}	0.0003	0.009		0.001
Methods	I,IM,F,A,O,X	I,A,O	I,A,IM,X,O	I,F,A,O,X,IM

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

